



P-Channel Enhancement MOSFET

Features

- Drain-Source Breakdown Voltage V_{DSS} .60 V
- Drain-Source On-Resistance
 $R_{DS(ON)}$ 170mΩ, at $V_{GS} = -10V$, $I_D = -1.8A$
 $R_{DS(ON)}$ 200mΩ, at $V_{GS} = -4.5V$, $I_D = -1.4A$
- Continuous Drain Current at $T_C=25^{\circ}\text{C}$ $I_D = -1.9A$
- Advanced high cell density Trench Technology
- RoHS Compliance & Halogen Free

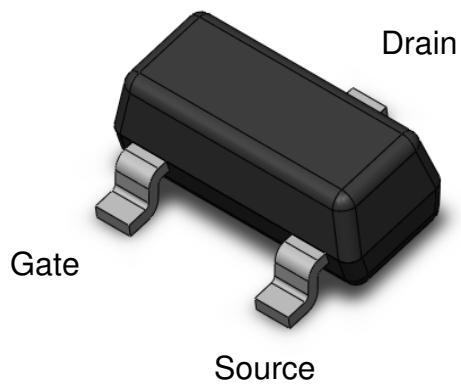
Description

The CTL0196PS-R3 is the P-Channel logic enhancement mode power field effect transistors are produced using high cell density, DMOS trench technology. This high density process is especially tailored to minimize on-state resistance.

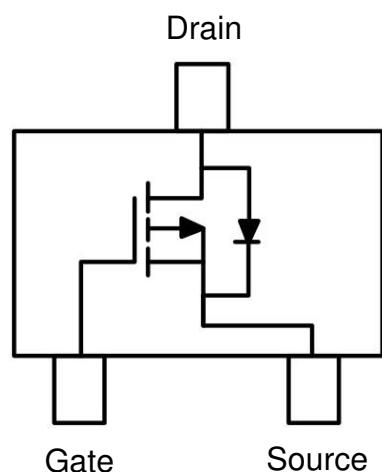
Applications

- Power Management
- Battery Powered System
- DC/DC Converter
- Load Switch
- DSC
- LCD Display inverter

Package Outline



Schematic





CTL0196PS-R3

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Absolute Maximum Rating at 25°C

Symbol	Parameters	Test Conditions	Min	Notes
V _{DS}	Drain-Source Voltage	-60	V	
V _{GS}	Gate-Source Voltage	±20	V	
I _D	Continuous Drain Current	-1.9	A	1
I _{DM}	Pulsed Drain Current	-7.6	A	1
P _D	Total Power Dissipation	1.4	W	2
T _{STG}	Storage Temperature Range	-55 to 150	°C	
T _J	Operating Junction Temperature Range	-55 to 150	°C	

Thermal Characteristics

Symbol	Parameters	Test Conditions	Min	Typ	Max	Units	Notes
R _{OJA4}	Thermal Resistance Junction-Ambient (t=10s)		--	90	--	°C /W	1,4



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Electrical Characteristics $T_A = 25^\circ\text{C}$ (unless otherwise specified)

Static Characteristics

Symbol	Parameters	Test Conditions	Min	Typ	Max	Units	Notes
V_{BDSS}	Drain-Source Breakdown Voltage	$V_{GS} = 0V, I_D = -250\mu\text{A}$	-60	-	-	V	
I_{DSS}	Drain-Source Leakage Current	$V_{DS} = -60V, V_{GS} = 0V$	-	-	-1	μA	
I_{GSS}	Gate-Source Leakage Current	$V_{GS} = \pm 20V, V_{DS} = 0V$	-	-	± 100	nA	

On Characteristics

Symbol	Parameters	Test Conditions	Min	Typ	Max	Units	Notes
$R_{DS(ON)}$	Drain-Source On-Resistance	$V_{GS} = -4.5V, I_D = -1.4A$	-	170	215	$\text{m}\Omega$	3
		$V_{GS} = -10V, I_D = -1.8A$	-	200	260	$\text{m}\Omega$	
$V_{GS(th)}$	Gate-Source Threshold Voltage	$V_{GS} = V_{DS}, I_D = -250\mu\text{A}$	-1	---	-3	V	3

Dynamic Characteristics

Symbol	Parameters	Test Conditions	Min	Typ	Max	Units	Notes
C_{iss}	Input Capacitance	$V_{GS} = 0V,$ $V_{DS} = -25V$ $f = 1\text{MHz}$	-	365	-	pF	3
C_{oss}	Output Capacitance		-	40	-		
C_{rss}	Reverse Transfer Capacitance		-	12	-		

Switching Characteristics

Symbol	Parameters	Test Conditions	Min	Typ	Max	Units	Notes
$T_{D(ON)}$	Turn-On Delay Time	$V_{DS} = -30V,$ $V_{GS} = -10V,$ $R_G = 3.3\Omega,$ $R_L = 30\Omega,$	-	20	-	ns	3
T_R	Rise Time		-	33	-		
$T_{D(OFF)}$	Turn-Off Delay Time		-	5.2	-		
T_F	Fall Time		-	3.8	-		
Q_G	Total Gate Charge	$V_{DS} = -48V,$ $V_{GS} = -4.5V,$ $I_D = -1A$	-	6.3	-	nC	3
Q_{GS}	Gate-Source Charge		-	2.3	-		
Q_{GD}	Gate-Drain Charge		-	1.8	-		

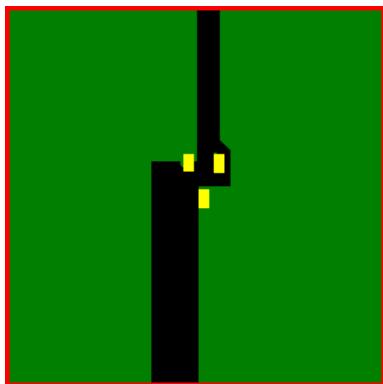


Drain-Source Diode Characteristics

Symbol	Parameters	Test Conditions	Min	Typ	Max	Units	Notes
V _{SD}	Body Diode Forward Voltage	V _{GS} = 0V, I _D = -1.9A	-	-	-1.2	V	
I _{SD}	Body Diode Continuous Current		-	-	-1.9	A	1

Note:

1. The power dissipation is limited by 150°C junction temperature.
2. Device mounted on a glass-epoxy board



FR-4
25.4 × 25.4 mm .
2 Oz Copper

Test Board

3. The data tested by pulsed , pulse width $\leq 300\mu\text{s}$, duty cycle $\leq 2\%$
4. Thermal Resistance follow JESD51-3.



Typical Characteristic Curves

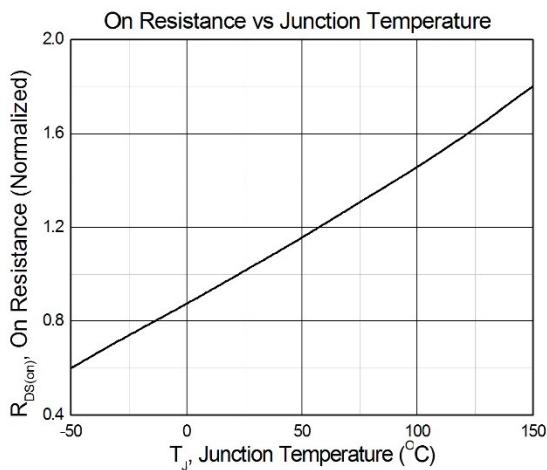


Figure 1

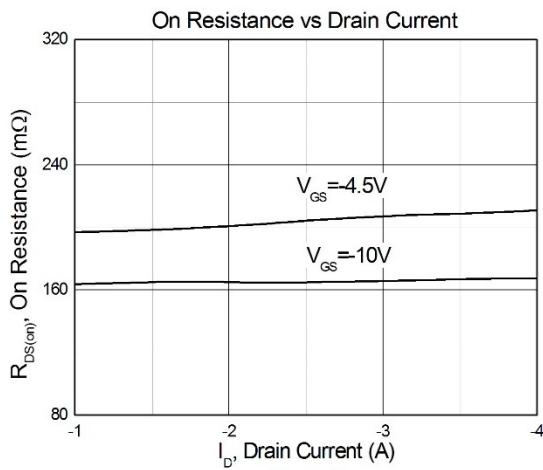


Figure 2

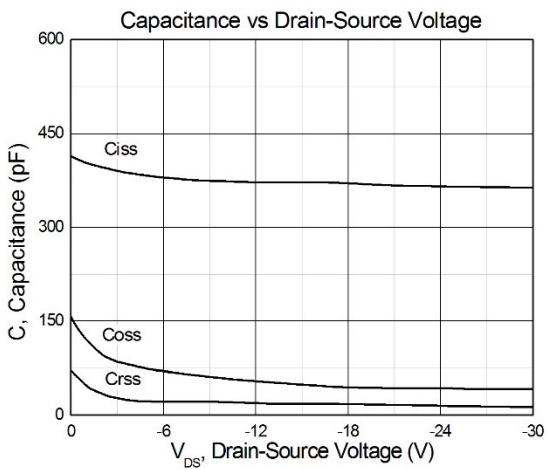


Figure 3

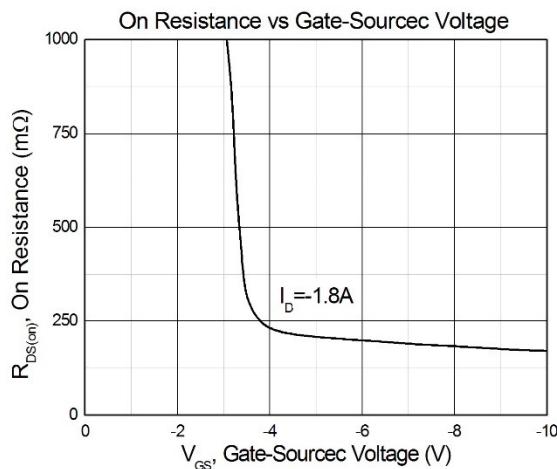


Figure 4

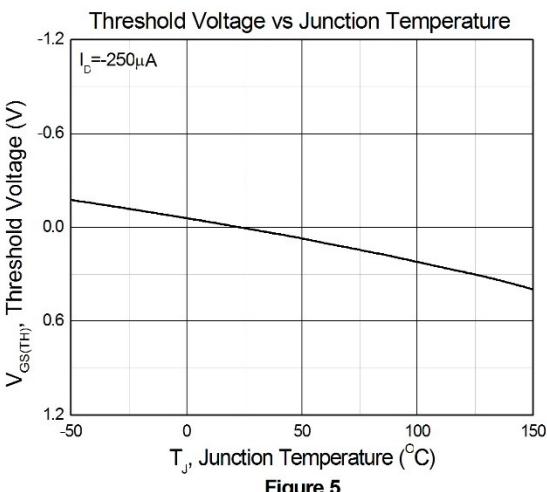


Figure 5

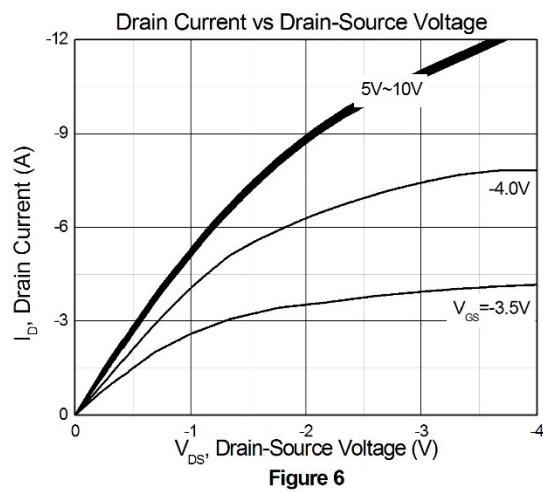


Figure 6



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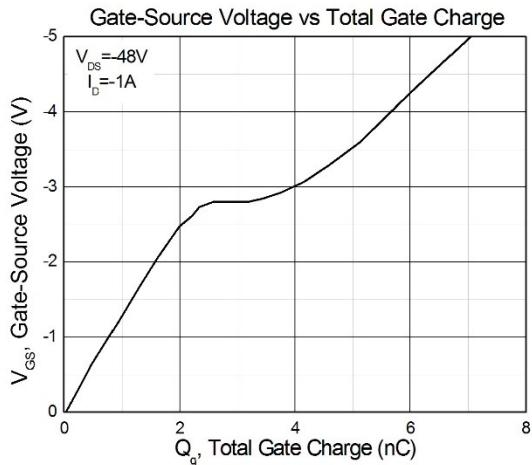


Figure 7

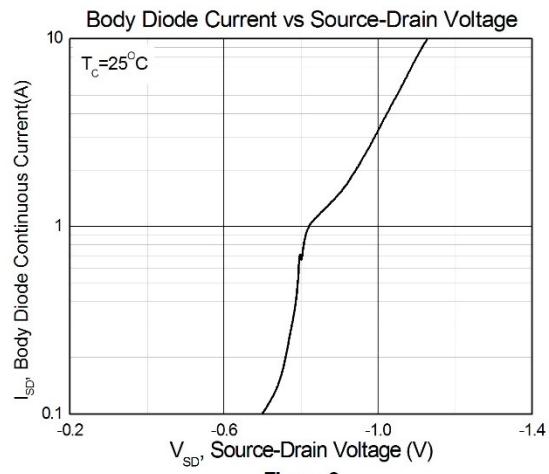


Figure 8



Test Circuits & Waveforms

Figure 9: Gate Charge Test Circuit

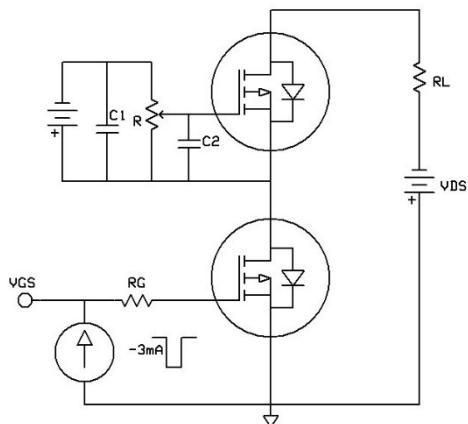


Figure 10: Gate Charge Waveform

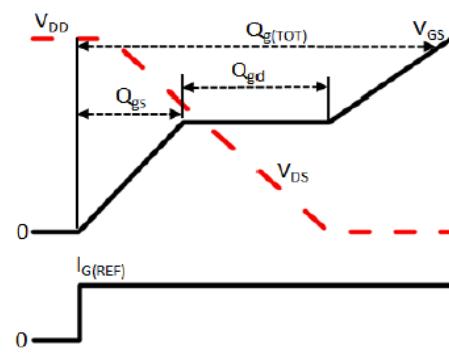


Figure 11: Switching Time Test Circuit

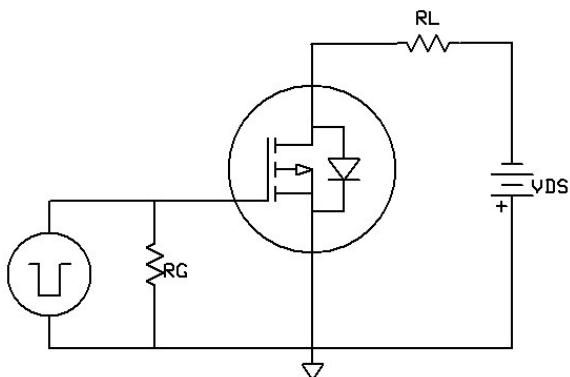
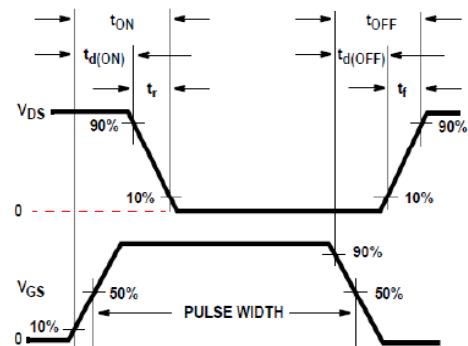
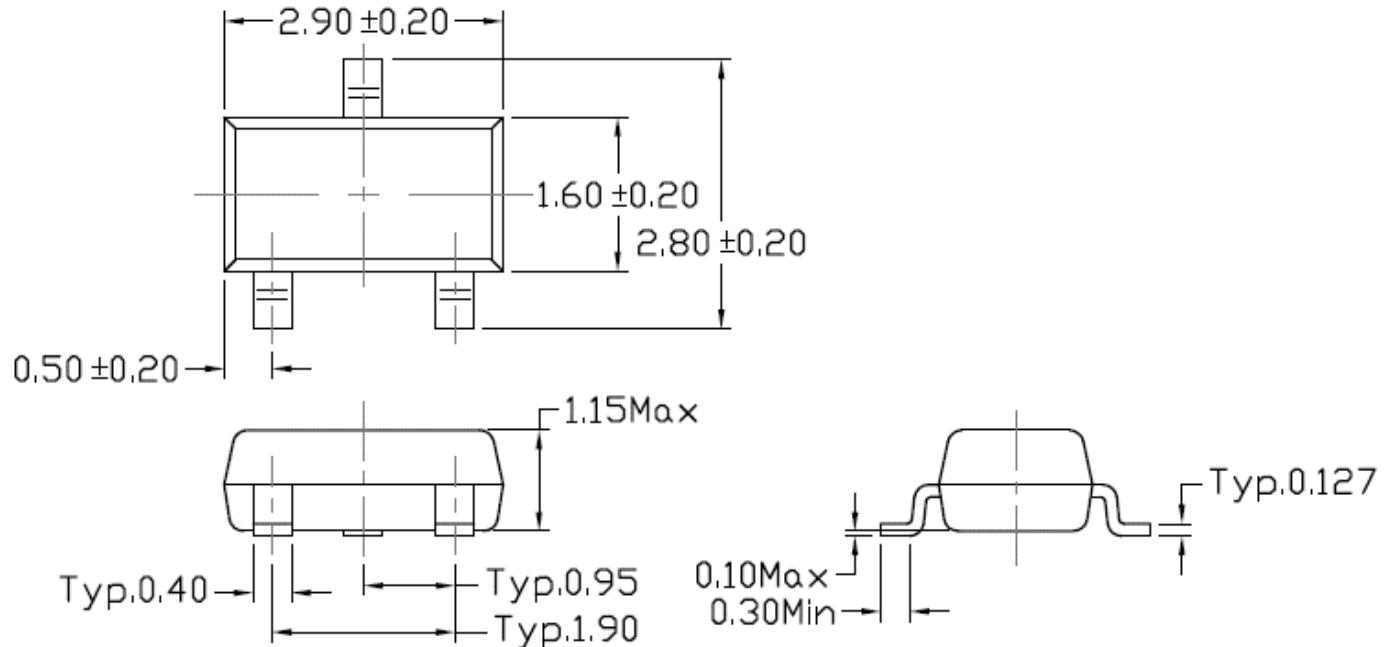


Figure 12: Switching Time Waveform

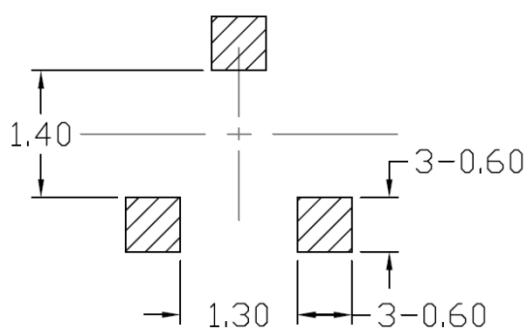




Package Dimension (SC-59)



Recommended pad layout for surface mount leadform

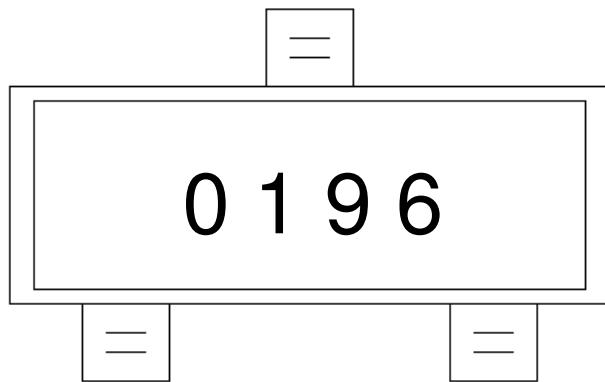




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Marking Information



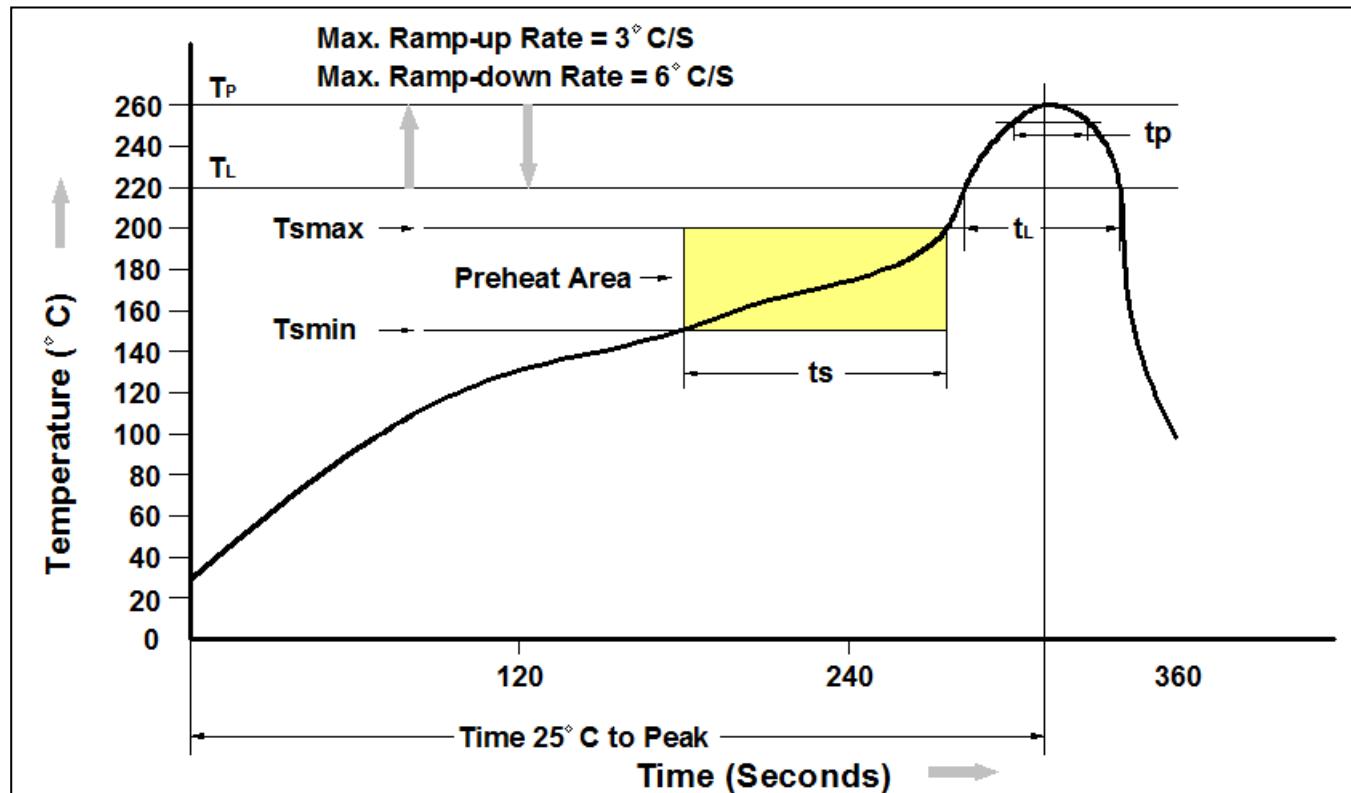
0196: Device Number

Ordering Information

Part Number	Description	Quantity
CTL0196PS-R3	SC-59 Reel	3000 pcs



Reflow Profile



Profile Feature	Pb-Free Assembly Profile
Temperature Min. (T _{smin})	150°C
Temperature Max. (T _{smax})	200°C
Time (t _s) from (T _{smin} to T _{smax})	60-120 seconds
Ramp-up Rate (t _L to t _P)	3°C/second max.
Liquidous Temperature (T _L)	217°C
Time (t _L) Maintained Above (T _L)	60 – 150 seconds
Peak Body Package Temperature	260°C +0°C / -5°C
Time (t _P) within 5°C of 260°C	30 seconds
Ramp-down Rate (T _P to T _L)	6°C/second max
Time 25°C to Peak Temperature	8 minutes max.



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